

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICELIST OF REFERENCES CITED BY APPLICANT(S)  
(Use several sheets if necessary)ATTY DOCKET NO.  
00862.022498APPLICATION NO.  
Not Yet Assigned

APPLICANT

Taka Yonehara, et al.

FILING DATE

Currently herewith

GROUP

Not Yet Assigned

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Bu	5,206,749	4/27/93	Zavracky et al.	359	59	
Bu	5,256,562	10/26/93	Vu et al.	437	86	
Bu	5,811,348	9/22/98	Matsushita, et al.	438	455	
Bu	6,107,213	8/22/00	Tayanaka, et al.	438	762	
Bu	5,985,742	11/16/99	Henley, et al.	438	515	
Bu	5,856,229	1/5/99	Sakaguchi, et al.	438	406	

31000 U.S. PTO  
10/059144  
01/31/02

## FOREIGN PATENT DOCUMENTS

	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
Bu	9-312349	12/2/97	Japan			Abstract
Bu	886 300	12/23/98	EP			

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)


EXAMINER

Brook Kebede

DATE CONSIDERED

2/2/2004

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Sheet 1 of 1

FORM PTO 1449 (modified)  U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE  LIST OF REFERENCES CITED BY APPLICANT(S) <small>(Use several sheets if necessary)</small>		ATTY DOCKET NO. <b>00862.022498.</b>	APPLICATION NO. <b>10/059,144</b>	
<div style="position: relative; height: 100px;"> <div style="position: absolute; top: 0; left: 0; width: 100%; height: 100%; border: 1px solid black; border-radius: 50%; text-align: center; line-height: 100px;">             018              JAN 10 2003              PTO           </div> </div>		APPLICANT <b>TAKAO YONEHARA, et al.</b>		
		FILING DATE <b>January 31, 2002</b>		GROUP <b>2812</b>

  

U.S. PATENT DOCUMENTS							
*EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
<i>bu</i>	6,075,280	06/13/00	Yung et al.	257	620	X	
<i>bu</i>	6,136,668	10/24/00	Tamaki, et al.	438	462		
<i>bu</i>	6,186,384	02/13/01	Sawada	225	2		
<i>bu</i>	6,465,329	10/15/02	Glenn	438	462		
<i>bu</i>	2002/0076904	06/20/02	Imler	438	462		
<i>bu</i>	2002/0100941	08/01/02	Yonehara, et al.	257	359		

  

FOREIGN PATENT DOCUMENTS							
	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT	

  

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)		

  

EXAMINER <i>Brook K. Gedd</i>	DATE CONSIDERED <i>2/2/2004</i>
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U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICE

AUG 19 2002

PRIORITY DOCKET NO. 00862.022498

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(Use several sheets if necessary)

APPLICANT TAKAO YONEHARA, et al.

FILING DATE January 31, 2002

GROUP 2812

## U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
Bu		6,190,937	02/20/2001	Nauagawa, et al.	438	67	
Bu		6,222,513	03/10/1998	Howard, et al.	345	84	
Bu		6,258,698	07/10/2001	Iwasaki, et al.	438	455	
Bu		6,306,729	10/23/2001	Sauaguchi, et al.	438	458	
Bu		6,331,208	12/18/2001	Nishida, et al.	117	89	
Bu		6,342,433	01/29/2002	Ohmi, et al.	438	455	
Bu		6,382,292	05/07/2002	Ohmi, et al.	156	584	

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		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES/NO/ OR ABSTRACT
Bu	EP	1 122 794	08/08/2001	Europe			
Bu	EP	858 110	08/12/1998	Europe			
Bu	EP	849 788	06/24/1998	Europe			
Bu	JP	11-316397	11/16/1999	Japan	G02F		Abstract

## OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

Bu		Shimoda, T., et al, "Surface Free Technology By Laser Annealing (SUFTLA)" International Electron Devices Meeting 1999. IEDM. Technical Digest. Washington, DC, Dec. 5 to 8, 1999, New York, NY: IEEE, US, August 1, 1999 (1999-08-01), pages 289 to 292, XP000933199 ISBN: 0-7803-5411-7.					

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